

| <b>FORM PTO-1449</b>  |    |   |          | <b>Atty. Docket No.</b><br>XA-9339C     |       | <b>Appln. No.</b><br>10/614,242 |                   |
|---|----|---|----------|---|-------|---------------------------------|-------------------|
| <b><u>LIST OF DOCUMENTS CITED BY APPLICANT</u></b>  |    |   |          | <b>Applicant</b><br>Yuichi OKUDA et al. |       |                                 |                   |
| <b>W. Q. Nguyen</b><br><b>Primary Examiner</b>  |    |   |          | <b>Filing Date</b><br>HEREWITH          |       | <b>Group</b><br>2818            |                   |
| <b>U. S. PATENT DOCUMENTS</b>   |    |   |          |   |       |                                 |                   |
| Examiner Initial  |    | Document Number   | Date     | Name                                    | Class | Sub-class                       | Filing Date       |
| W   | AA | 6,194,932   | 2/27/01  | Takemae et al.                          | 327   | 158                             | _____             |
| W   | AB | 6,457,688   | 12/00    | Tamura et al.                           | 375   | 348                             | _____             |
| W   | AC | 6,069,508   | 5/30/00  | Takai                                   | 327   | 61                              | _____             |
| W   | AD | 6,172,537   | 1/01     | Kanou et al.                            | 327   | 99                              | _____             |
| W   | AE | 5,754,838   | 5/19/98  | Shibata et al.                          | 395   | 559                             | _____             |
| W   | AF | 5,953,284   | 9/14/99  | Baker et al.                            | 365   | 233                             | _____             |
| W   | AG | 6,166,990   | 12/26/00 | Ooishi et al.                           | 365   | 233                             | _____             |
| W   | AH | 6,222,406   | 4/01     | Noda et al.                             | 327   | 269                             | _____             |
| W   | AI | 6,081,142   | 6/27/00  | Douchi et al.                           | 327   | 158                             | _____             |
| W   | AJ | 5,936,441   | 8/10/99  | Kurita                                  | 327   | 141                             | _____             |
| W   | AK | 5,926,053   | 7/20/99  | McDermott et al.                        | 327   | 298                             | _____             |
| <b>FOREIGN PATENT DOCUMENTS</b>   |    |   |          |   |       |                                 |                   |
| Examiner Initial  |    | Document Number   | Date     | Country                                 | Class | Sub-class                       | Translation       |
| W   | AL | 2000-188540   | 7/00     | Japan                                   | _____ | _____                           | cited by Examiner |
| W   | AM | 2000-124796   | 4/00     | Japan                                   | _____ | _____                           | cited by Examiner |
| W   | AN | 2000-183730   | 6/00     | Japan                                   | _____ | _____                           | cited by Examiner |
| W   | AO | 2-90666   | 3/30/90  | Japan                                   | _____ | _____                           | Abstract          |
| W   | AP | 11-55145  | 2/26/99  | Japan                                   | _____ | _____                           | Abstract          |
| W   | AQ | 10-171774   | 6/26/98  | Japan                                   | _____ | _____                           | Abstract          |
| <b>OTHER</b> (including author, title, date, pertinent pages, etc.)   |    |   |          |   |       |                                 |                   |
| W   | AR | Johnson et al., "A Variable Delay Line PLL for CPU-Coprocessor Synchronization",<br>IEEE Journal of Solid-State Circuits, Vol. 23, No. 5, pp. 1218-1223, October 1998 |          |   |       |                                 |                   |
| <b>Examiner</b><br>V. Nguyen  |    |   |          | <b>Date Considered</b><br>6/25/04       |       |                                 |                   |
| <b>EXAMINER:</b> Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant. |    |   |          |   |       |                                 |                   |

W. Q. Nguyen  
Primary Examiner

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| <i>W</i>   | AA* | 6,191,632       | 12/20/01 | Iwata                                   | 327   | 295                             | <i>    </i> |
| <i>W</i>   | AB* | 5,883,534       | 3/16/99  | Kondoh et al.                           | 327   | 156                             | <i>    </i> |
| <i>W</i>   | AC* | 6,377,511       | 4/23/02  | Okuda et al.                            | 365   | 233                             | <i>    </i> |
| <i>W</i>   | AD* | 6,373,303       | 4/16/02  | Akita                                   | 327   | 156                             | <i>    </i> |
| <i>W</i>   | AE* | 5,619,148       | 4/8/97   | Guo                                     | 327   | 3                               | <i>    </i> |
| <i>W</i>   | AF* | 2001/0021953    | 09/13/01 | Nakashima                               | 710   | 5                               | <i>    </i> |
| <i>W</i>   | AG* | 2002/0008589    | 01/24/02 | Lanoman et al.                          | 331   | 34                              | <i>    </i> |
| <i>W</i>   | AH* | 2002/0033737    | 3/21/02  | Staszewski et al.                       | 331   | 17                              | <i>    </i> |
| <i>W</i>   | AI* | 6,452,859       | 09/17/02 | Shimano et al.                          | 365   | 230.06                          | <i>    </i> |
| <i>W</i>   | AJ* | 6,172,537       | 01/09/01 | Kanou et al.                            | 327   | 99                              | <i>    </i> |
| <i>W</i>   | AK* | 6,518,813       | 02/11/03 | Usui                                    | 327   | 291                             | <i>    </i> |
| <b>FOREIGN PATENT DOCUMENTS</b>  |     |                 |          |   |       |                                 |             |
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|  | AL  |                 |          |   |       |                                 |             |
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|  | AN  |                 |          |   |       |                                 |             |
|  | AO  |                 |          |   |       |                                 |             |
|  | AP  |                 |          |   |       |                                 |             |
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| Examiner Initial   |     | Document Number | Date     | Name                                    | Class | Sub-class                       | Filing Date       |
| <i>W</i>   | AA+ | 6,463,008       | 10/08/02 | Okuda et al.                            | 365   | 233                             | <u>          </u> |
| <i>W</i>   | AB+ | 2001/0017558    | 08/30/01 | Hanzawa et al.                          | 327   | 165                             | <u>          </u> |
| <i>W</i>   | AC+ | 6,336,901       | 01/08/02 | Itonaga et al.                          | 600   | 499                             | <u>          </u> |
| <i>W</i>   | AD+ | 6,281,725       | 08/28/01 | Hanzawa et al.                          | 327   | 152                             | <u>          </u> |
| <i>W</i>   | AE+ | 6,269,051       | 07/31/01 | Funaba et al.                           | 365   | 233                             | <u>          </u> |
| <i>W</i>   | AF+ | 6,222,792       | 04/24/01 | Hanzawa et al.                          | 365   | 233                             | <u>          </u> |
|  | AG+ |                 |          |   |       |                                 |                   |
|  | AH+ |                 |          |   |       |                                 |                   |
|  | AI+ |                 |          |   |       |                                 |                   |
|  | AJ+ |                 |          |   |       |                                 |                   |
|  | AK+ |                 |          |   |       |                                 |                   |
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|  | AM  |                 |          |   |       |                                 |                   |
|  | AN  |                 |          |   |       |                                 |                   |
|  | AO  |                 |          |   |       |                                 |                   |
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